

IN THE U.S. PATENT AND TRADEMARK OFFICE

In re application of: Michinobu TANIOKA et al.

Conf.:

Appl. No.: **NEW NON-PROVISIONAL**

Group:

Filed: October 29, 2003

Examiner:

Title: SEMICONDUCTOR DEVICE INSPECTION APPARATUS
AND INSPECTION METHOD

PRELIMINARY AMENDMENT

Assistant Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

October 29, 2003

Sir:

The following preliminary amendments and remarks are respectfully submitted in connection with the above-identified application.

Amendments to the Specification begin on page 2 of this paper.

Remarks begin on page 3 of this paper.

An **Appendix** is attached following the signature page of this paper.